## Notice of References Cited Application/Control No. 10/808,081 Examiner Ian Jen Applicant(s)/Patent Under Reexamination WHITTON, MATTHEW D. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,241,477 A	08-1993	Narita, Yasushi	701/59
*	В	US-5,304,102 A	04-1994	Narita et al.	475/125
*	С	US-5,745,382 A	04-1998	Vilim et al.	706/16
*	D	US-5,779,594 A	07-1998	Minowa et al.	477/156
*	E	US-6,216,066 B1	04-2001	Goebel et al.	701/29
*	F	US-6,243,637 B1	06-2001	Minowa et al.	701/51
*	G	US-2001/0016539 A1	08-2001	Yuasa et al.	477/143
*	н	US-6,334,833 B1	01-2002	Ochi et al.	477/143
*	_	US-6,428,440 B2	08-2002	Yuasa et al.	475/125
*	7	US-6,503,165 B1	01-2003	Kubo et al.	475/125
*	К	US-6,961,646 B2	11-2005	Soliman et al.	701/51
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification .
	N					
	0					
	Ρ				·	
	Q					
	R					•
	s					
	Т			ı		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	<b>v</b>	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.